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U.S. UTILITY Patent Application

O.I.P.E.	PATENT DATE
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APPLICATION NO. 09/883449	CONT/PRIOR	CLASS 714	SUBCLASS 763 741	ART UNIT 2133	EXAMINER T. H. HUNG
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APPLICANTS
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TITLE
Method to verify the performance of bist circuitry for testing embedded memory

PTO-2040
12/89

ISSUING CLASSIFICATION

[illegible]

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
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